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CHARACTERISING A CUT PHOTOVOLTAIC  
CELL**(30) **Foreign Application Priority Data**

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Cedex 09 (FR); **Samuel HARRISON**,  
Grenoble Cedex 09 (FR);  
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Cedex 09 (FR)(57) **ABSTRACT**

A method for electrically characterising a cut photovoltaic cell, includes measuring the feature I-V of the uncut cell; cutting the cell into a plurality of sub-cells; measuring the feature I-V of each sub-cell not electrically connected to the other sub-cells; measuring the feature I-V of a set comprising all the sub-cells connected in parallel; determining, on the basis of the measured features I-V, performance parameters of the uncut cell, of each sub-set and of the set; computing, for each sub-cell, the difference between the value of the performance parameters of the sub-cell and that of the performance parameter of the uncut cell; and computing the difference between the value of the performance parameter of the set and the value of the performance parameter of the uncut cell.

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